

FD 9/29/2005

Substitute for form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/673843
		Filing Date	9/29/2005
		First Named Inventor	S. Mark Haugland
		Art Unit	2863
		Examiner Name	V. Taylor
Sheet 1 of 2	Attorney Docket Number	PAT009CON	

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No.	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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W	AA	US-	3,944,910	03-16-1976	Rau	/
W	AB	US-	4,185,238	01-22-1980	Huchital et al.	
W	AC	US-	4,209,247	06-24-1980	Urano et al.	
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W	AE	US-	4,780,679	10-25-1988	Kenyon et al.	
W	AF	US-	4,899,112	02-06-1990	Clark et al.	
W	AG	US-	4,968,940	11-06-1990	Clark et al.	
W	AH	US-	5,157,605	10-20-1992	Chandler et al.	
W	AI	US-	5,594,343	01-14-1997	Clark et al.	
W	AJ	US-	5,210,691	05-11-1993	Freedman et al.	
W	AK	US-	5,469,062	11-21-1995	Meyer, Jr.	
W	AL	US-	5,675,147	10-07-1997	Ekstrom et al.	
W	AM	US-	5,867,806	01-02-1999	Strickland et al.	
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W	AY	US-	6,344,746 B1	02-05-2002	Chunduru et al.	
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				LAST		

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ¹
W	AAC	Dielectric-Independent 2-MHz Propagation Resistivities, Peter T. Wu, John R. Lovell, Brian Clark, Stephen D. Bonner and Jacques R. Tabanou, Society of Petroleum Engineers, Inc. SPE 56448, 19 pages (1999).	
W	AAD	New Developments in 2- MHz Electromagnetic Wave Resistivity Measurements, S. Gianzero, G. A. Merchant, M. Haugland and R. Strickland, SPWLA 35th Annual Logging Symposium, pp. 1-25 (June 19-22, 1994).	
W	AAE	Vertical Deconvolution of 2 MHz Propagation Tools, Richard Rosthal, David Allen and Stephen Bonner, SPWLA 34th Annual Logging Symposium (June 13-16, 1993).	

Examiner Signature	<i>[Signature]</i>	Date Considered	6/1/2006
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U.S. PATENT DOCUMENTS					
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<u>W</u>	BA	Geometric Factor and Adaptive Deconvolution of MWD-PWR Tools, Q. Zhou, D. J. Hilliker and D. Norwood, The Log Analyst, pp. 390-398 (July-August, 1992).			
<u>W</u>	BB	Reconciling Differences in Depth of Investigation Between 2- MHz Phase Shift and Attenuation Resistivity Measurements, Tarek Habashy and Barbara Anderson, SPWLA 32nd Annual Logging Symposium, pp. 1-20 (June 16-19, 1991).			
<u>W</u>	BC	Complex Variables and Applications 5th Ed., Ruel V. Churchill and James Ware Brown, 2 cover pages and pp. 48-50 (1990).			
<u>W</u>	BD	Waves and Fields In Inhomogeneous Media, Transients, Weng Cho Chew, 2 cover pages, pp. 244-246, 360-365 and 485-487 (1990).			
<u>W</u>	BE	Algorithm 624: Triangulation and Interpolation at Arbitrarily Distributed Points In the Plane, Robert J. Renka, ACM Transaction on Mathematical Software, Vol. 10, pp. 440-442 (December 4, 1984).			
<u>W</u>	BF	A Triangle-Based C ¹ Interpolation Method, R. J. Renka and A. K. Cline, rocky Mountain Journal of Mathematics, Vol. 14, No. 1, pp. 223-237 (Winter 1984).			
<u>W</u>	BG	Geophysics, A Journal of General and Applied Geophysics, Published by The Society of Exploration Geophysicists, Vol. XXVII, No. 6, Part 1, cover page and pp. 828-858 (December 1962).			
<u>W</u>	BH	MORAN, J. H. and CHEMALI, R. E., More on the Laterolog Device, Geophysical Prospecting 27, pp. 902-930 (1979).			
<u>W</u>	BI	Effect of Tool Eccentricity on Some Electrical Well-Logging Tools, John R. Lovell and Weng Cho Chew, IEEE Transactions on Geoscience and Remote Sensing, Vol. 28, No. 1, pp. 127-136 (January 1990).			
<u>W</u>	BJ	BADEA, EUGENE A. and EVERETT, MARK E. 3-D Finite Element Analysis of Induction Logging, 4 pages (date unknown). NOT CONSIDERED			
<u>W</u>	BK	Fundamental Analysis of Remote-Field Eddy-Current Effect, IEEE Transactions on Magnetics, Vol. 32, No. 4, pp. 3195-3211 (July 1996).			
<u>W</u>	BL	Numerical Recipes, The Art of Scientific Computing, © Cambridge Press 1986 and © Numerical Recipes Software, 2 cover pages, pp. 52-65 and 520-527 (1986).			
<u>W</u>	BM	NAG Fortran Library Manual Mark 18, © The Numerical Algorithms Group Limited, Vol. 4, D04-4E04L cover pages and pp. E04.1 - E04.16 and 1-6 (September 1997).			
<u>W</u>	BN	New Discovery with Important Implications of LWD Propagation Resistivity Processing and Interpretation, S. Mark Haugland, SPWLA 42nd Annual Logging Symposium, pp. 1-14 (June 17-20, 2001).			
<u>W</u>	BO	Handbook of Electromagnetic Materials, Monolithic and Composite Versions and Their Applications, Perambur S. Neelakanta, PhD., C.Eng., © 1995 by CRC Press, Inc., cover pages and p. 46.			
<u>W</u>	BP	Estimation Of Water Content and Porosity Using Combined Radar and Geoelectrical Measurements, Grit Dannowski and Ugur Yaramanci, Technical University of Berlin, Dept. of Applied Geophysics, July 28, 1999.			
<u>W</u>	BQ	Comparisons of Wireline and LWD Resistivity Highlight Resistivity Frequency Dispersion In Sedimentary Formations, Roland Chemali, Dale Heysee, G. A. Merchang, Charles Jackson, SPWLA 36th Annual Logging Symposium, pp. 1-12 (June 26-29, 1995).			
<u>W</u>	BR	In-situ Measurement of Resistivity Dispersions (or lack of it) Using MWD Propagation Resistivity Tools, W. Hal Meyer, SPWLA 40th Annual Logging Symposium, pp. 1-14, (May 30 - June 3, 1999).			
Examiner Signature	<u>V. Taylor</u>			Date Considered	<u>6/1/2006</u>
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				Art Unit	2863		
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